


IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) CB SCHEME

CB TEST CERTIFICATE

Product	Intel® NUC
Name and address of the applicant	INTEL CORPORATION 2200 MISSION COLLEGE BLVD SANTA CLARA, CA 95054-1537 USA
Name and address of the manufacturer	INTEL CORPORATION 2200 MISSION COLLEGE BLVD SANTA CLARA, CA 95054-1537 USA
Name and address of the factory <small>Note: When more than one factory, please report on page 2</small>	GOLDEN ELITE TECHNOLOGY (SHEN ZHEN) LTD 1 NAN HUAN RD SHAJING BAO AN SHENZHEN GUANGDONG 518104 CHINA <input type="checkbox"/> Additional Information on page 2
Ratings and principal characteristics	1) 19 Vdc, 3.43 A 2) 19 Vdc, 3.42 A
Trademark (if any)	
Type of Customer's Testing Facility (CTF) Stage used	
Model / Type Ref.	1) xNUC6xAYx, xNUC7xBNHx, xNUC7xBNKx 2) xNUC7xJYx (where x can be a combination of alphanumeric characters, none or blank)
Additional information (if necessary may also be reported on page 2)	Additionally evaluated to EN 62368-1: 2014 / A11: 2017; National Differences specified in the CB Test Report. <input checked="" type="checkbox"/> Additional Information on page 2
A sample of the product was tested and found to be in conformity with	IEC 62368-1(ed.2)
As shown in the Test Report Ref. No. which forms part of this Certificate	ATTCB106090 issued on 2018-01-15

This CB Test Certificate is issued by the National Certification Body



- UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA
- UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK
- UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN
- UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

For full legal entity names see www.ul.com/ncbnames

Date: 2018-01-15

Signature:

Jan-Erik Storgaard